EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L2	4	(parallel near test\$4).clm. and chip and (padgroup or pad adj group)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/20 11:18
L3	17	parallel near (test\$4 or prob\$4) and chip and (padgroup or pad adj group)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/20 11:25
L4	1	parallel near (test\$4 or prob\$4) and chip and (padgroup or pad near group) and (inspect\$4 near tool or sem or electron near microscop\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/20 11:39
L5	264	parallel near (test\$4 or prob\$4) and chip and (inspect\$4 near tool or sem or electron near microscop\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/20 11:40
L6	33	parallel near (test\$4 or prob\$4) same chip and (inspect\$4 near tool or sem or electron near microscop\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON ·	2008/01/20 11:41
L7	42	("4573146" "4769784" "5110754" "5212442" "5241496" "5257229" "5291454" "5291455" "5297099" "5307318" "5355340" "5381373" "5467356" "5473198").PN. OR ("5657284").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2008/01/20 11:58
L8	1	parallel near (test\$4 or prob\$4) same (padgroup or pad with group\$4) and (inspect\$4 near tool or sem or electron near microscop\$3 or stm)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/20 12:09
L9	1	parallel with (test\$4 or prob\$4) same (padgroup or pad with group\$4) and (inspect\$4 near tool or sem or electron near microscop\$3 or stm)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON .	2008/01/20 12:09

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L10	109	parallel with (test\$4 or prob\$4) same (pads or padgroup or pad with group\$4) and (inspect\$4 near tool or sem or electron near microscop\$3 or stm)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/20 12:10
L11	14	parallel near3 (test\$4 or prob\$4) same (prob\$4 or test\$4 or bond\$4) near (pads or padgroup or pad with group\$4) and (inspect\$4 near tool or sem or electron near microscop\$3 or stm)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/20 12:36
L12	212	parallel near3 (test\$4 or prob\$4) and (prob\$4 or test\$4 or bond\$4) near (pads or padgroup or pad with group\$4) and (inspect\$4 near tool or sem or electron near microscop\$3 or stm)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/20 12:39
L13	165	parallel near (test\$4 or prob\$4) and (prob\$4 or test\$4 or bond\$4) near (pads or padgroup or pad with group\$4) and (inspect\$4 near tool or sem or electron near microscop\$3 or stm)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/20 12:39
L14		(parallel near (test\$4 or prob\$4) and (prob\$4 or test\$4 or bond\$4) near (pads or padgroup or pad with group\$4) and (inspect\$4 near tool or sem or electron near microscop\$3 or stm)).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR .	ON	2008/01/20 12:40
L15	166	parallel near (test\$4 or prob\$4) and (prob\$4 or test\$4 or bond\$4) near (pads or padgroup or pad with group\$4) and (inspect\$4 near tool or sem or scan\$4 near microscop\$3 or stm)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR .	ON	2008/01/20 12:41
L16	4	parallel near (test\$4 or prob\$4) same (prob\$4 or test\$4 or bond\$4) near (pads or padgroup or pad with group\$4 or structure) and (inspect\$4 near tool or sem or scan\$4 near microscop\$3 or stm)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/20 12:42